

ABSTRACT

A storage device testing system (100) includes at least one robotic arm (200) defining a first axis (205) substantially normal to a floor surface (10). The robotic arm is operable to rotate through a predetermined arc about and extend radially from the first axis. Multiple racks (300) are arranged around the robotic arm for servicing by the robotic arm. Each rack houses multiple test slots (310) that are each configured to receive a storage device transporter (550) configured to carry a storage device (500) for testing.

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